

SNVS333C-NOVEMBER 2004-REVISED MARCH 2005

LM5107 100V / 1.4A Peak Half Bridge Gate Driver

Check for Samples: LM5107

FEATURES

- Drives Both a High Side and Low Side N-Channel MOSFET
- High Peak Output Current (1.4A Sink / 1.3A Source)
- Independent TTL compatible inputs
- Integrated Bootstrap Diode
- Bootstrap Supply Voltage to 118V DC
- Fast Propagation Times (27 ns Typical)
- Drives 1000 pF Load with 15ns Rise and Fall Times
- Excellent Propagation Delay Matching (2 ns Typical)
- Supply Rail Under-Voltage Lockout
- Low Power Consumption
- Pin Compatible with ISL6700

TYPICAL APPLICATIONS

- Current Fed Push-Pull Converters
- Half and Full Bridge Power Converters
- Solid State Motor Drives
- Two Switch Forward Power Converters

DESCRIPTION

The LM5107 is a low cost high voltage gate driver, designed to drive both the high side and the low side N-Channel MOSFETs in a synchronous buck or a half bridge configuration. The floating high-side driver is capable of working with rail voltages up to 100V. The outputs are independently controlled with TTL compatible input thresholds. An integrated on chip high voltage diode is provided to charge the high side gate drive bootstrap capacitor. A robust level shifter technology operates at high speed while consuming low power and providing clean level transitions from the control input logic to the high side gate driver. Under-voltage lockout is provided on both the low side and the high side power rails. The device is available in the SOIC and the thermally enhanced WSON packages.

Package

- SOIC
- WSON (4 mm x 4 mm)

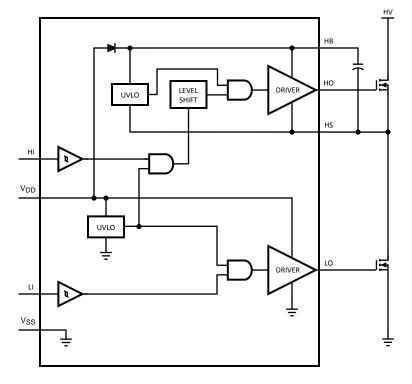


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Simplified Block Diagram



Connection Diagrams

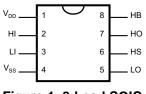


Figure 1. 8-Lead SOIC See D Package

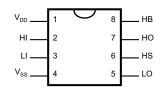


Figure 2. 8-Lead WSON See NGT0008A Package

PIN DESCRIPTIONS⁽¹⁾

Р	Pin #		Description	Application Information						
SOIC	WSON	Name	Description	Application mormation						
1	1	V _{DD}	Positive gate drive supply	Locally decouple to V_{SS} using low ESR/ESL capacitor located as close to IC as possible.						
2	2	НІ	High side control input	The LM5107 HI input is compatible with TTL input thresholds. Unused HI input should be tied to ground and not left open						
3	3	LI	Low side control input	The LM5107 LI input is compatible with TTL input thresholds. Unus LI input should be tied to ground and not left open.						
4	4	V _{SS}	Ground reference All signals are referenced to this ground.							
5	5	LO	LO Low side gate driver output Connect to the gate of the low side N-MOS device.							
6	6	HS	High side source connection	Connect to the negative terminal of the bootstrap capacitor and to the source of the high side N-MOS device.						
7	7	HO	High side gate driver output	Connect to the gate of the low side N-MOS device.						
8	8	НВ	High side gate driver positive supply rail	Connect the positive terminal of the bootstrap capacitor to HB and the negative terminal of the bootstrap capacitor to HS. The bootstrap capacitor should be placed as close to IC as possible.						

(1) For WSON package it is recommended that the exposed pad on the bottom of the LM5107 be soldered to ground plane on the PCB board and the ground plane should extend out from underneath the package to improve heat dissipation.



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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings⁽¹⁾⁽²⁾

V _{DD} to V _{SS}	-0.3V to 18V
HB to HS	-0.3V to 18V
LI or HI to V _{SS}	-0.3V to V _{DD} +0.3V
LO to V _{SS}	-0.3V to V _{DD} +0.3V
HO to V _{SS}	V_{HS} –0.3V to V_{HB} +0.3V
HS to $V_{SS}^{(3)}$	-5V to 100V
HB to V_{SS}	118V
Junction Temperature	-40°C to +150°C
Storage Temperature Range	-55°C to +150°C
ESD Rating HBM ⁽⁴⁾	2 kV

(1) Absolute Maximum Ratings indicate limits beyond which damage to the component may occur. Operating Ratings are conditions under which operation of the device is guaranteed. Operating Ratings do not imply guaranteed performance limits. For guaranteed performance limits and associated test conditions, see the Electrical Characteristics.

(2) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/Distributors for availability and specifications.

(3) In the application the HS node is clamped by the body diode of the external lower N-MOSFET, therefore the HS voltage will generally not exceed -1V. However in some applications, board resistance and inductance may result in the HS node exceeding this stated voltage transiently. If negative transients occur on HS, the HS voltage must never be more negative than V_{DD} - 15V. For example, if V_{DD} = 10V, the negative transients at HS must not exceed -5V.

(4) The human body model is a 100 pF capacitor discharged through a 1.5kΩ resistor into each pin. Pin 6, Pin 7 and Pin 8 are rated at 500V.

Recommended Operating Conditions

V _{DD}	8V to 14V
HS ⁽¹⁾	-1V to 100V
НВ	V _{HS} +8V to V _{HS} +14V
HS Slew Rate	< 50 V/ns
Junction Temperature	-40°C to +125°C

(1) In the application the HS node is clamped by the body diode of the external lower N-MOSFET, therefore the HS voltage will generally not exceed -1V. However in some applications, board resistance and inductance may result in the HS node exceeding this stated voltage transiently. If negative transients occur on HS, the HS voltage must never be more negative than V_{DD} - 15V. For example, if V_{DD} = 10V, the negative transients at HS must not exceed -5V.

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STRUMENTS

EXAS

Electrical Characteristics

Specifications in standard typeface are for $T_J = +25^{\circ}C$, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, $V_{DD} = V_{HB} = 12V$, $V_{SS} = V_{HS} = 0V$, No Load on LO or HO.

Symbol	Parameter	Conditions	Min ⁽¹⁾	Тур	Max ⁽¹⁾	Units
SUPPLY C	URRENTS			I	L	1
DD	V _{DD} Quiescent Current	LI = HI = 0V		0.3	0.6	mA
DDO	V _{DD} Operating Current	f = 500 kHz		2.1	3.4	mA
I _{HB}	Total HB Quiescent Current	LI = HI = 0V		0.06	0.2	mA
н _{во}	Total HB Operating Current	f = 500 kHz		1.6	3.0	mA
I _{HBS}	HB to V _{SS} Current, Quiescent	$V_{HS} = V_{HB} = 100V$		0.1	10	μA
нвѕо	HB to V _{SS} Current, Operating	f = 500 kHz		0.5		mA
	S LI and HI					
VIL	Low Level Input Voltage Threshold		0.8	1.8		V
V _{IH}	High Level Input Voltage Threshold			1.8	2.2	V
R _I	Input Pulldown Resistance		100	180	500	kΩ
UNDER VC	DLTAGE PROTECTION				•	
V _{DDR}	V _{DD} Rising Threshold	$V_{DDR} = V_{DD} - V_{SS}$	6.0	6.9	7.4	V
V _{DDH}	V _{DD} Threshold Hysteresis			0.5		V
V _{HBR}	HB Rising Threshold	$V_{HBR} = V_{HB} - V_{HS}$	5.7	6.6	7.1	V
V _{HBH}	HB Threshold Hysteresis			0.4		V
BOOT STR	AP DIODE		L			I.
V _{DL}	Low-Current Forward Voltage	$I_{VDD-HB} = 100 \ \mu A$ $V_{DL} = V_{DD} - V_{HB}$		0.58	0.9	V
V _{DH}	High-Current Forward Voltage	$I_{VDD-HB} = 100 \text{ mA}$ $V_{DH} = V_{DD} - V_{HB}$		0.82	1.1	V
R _D	Dynamic Resistance	I _{VDD-HB} = 100 mA		0.8	1.5	Ω
LO GATE I	DRIVER					
V _{OLL}	Low-Level Output Voltage	I_{LO} = 100 mA V _{OHL} = V _{LO} - V _{SS}		0.28	0.45	V
V _{OHL}	High-Level Output Voltage	$I_{LO} = -100 \text{ mA},$ $V_{OHL} = V_{DD} - V_{LO}$		0.45	0.75	V
OHL	Peak Pullup Current	$V_{LO} = 0V$		1.3		А
OLL	Peak Pulldown Current	$V_{LO} = 12V$		1.4		А
HO GATE I	DRIVER					
V _{OLH}	Low-Level Output Voltage	$I_{HO} = 100 \text{ mA}$ $V_{OLH} = V_{HO} - V_{HS}$		0.28	0.45	V
V _{OHH}	High-Level Output Voltage	$I_{HO} = -100 \text{ mA}$ $V_{OHH} = V_{HB} - V_{HO}$		0.45	0.75	V
онн	Peak Pullup Current	V _{HO} = 0V		1.3		А
I _{OLH}	Peak Pulldown Current	V _{HO} = 12V		1.4		А
	RESISTANCE			•	•	
θ _{JA} ⁽²⁾		SOIC		160		
	Junction to Ambient	WSON ⁽³⁾		40		°C/W

(1) Min and Max limits are 100% production tested at 25°C. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods. Limits are used to calculate National's Average Outgoing Quality Level (AOQL).

(2) The θ_{JA} is not a constant for the package and depends on the printed circuit board design and the operating conditions.

(3) 4 layer board with Cu finished thickness 1.5/1/1/1.5 oz. Maximum die size used. 5x body length of Cu trace on PCB top. 50 x 50mm ground and power planes embedded in PCB. See Application Note AN-1187.



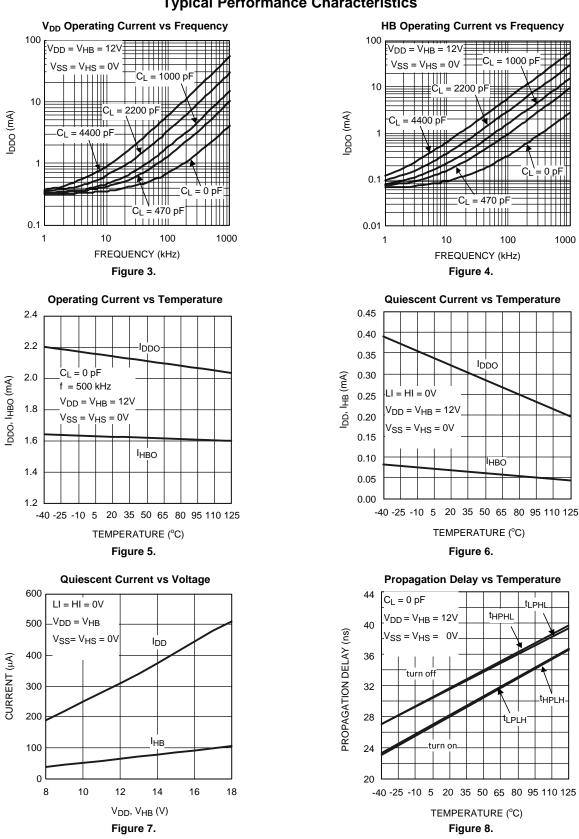
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Switching Characteristics

Specifications in standard typeface are for $T_J = +25^{\circ}$ C, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, $V_{DD} = V_{HB} = 12$ V, $V_{SS} = V_{HS} = 0$ V, No Load on LO or HO.

Symbol	Parameter	Conditions	Min ⁽¹⁾	Тур	Max ⁽¹⁾	Units
LM5100A			u.			
t _{LPHL}	Lower Turn-Off Propagation Delay (LI Falling to LO Falling)			27	56	ns
t _{HPHL}	Upper Turn-Off Propagation Delay (HI Falling to HO Falling)			27	56	ns
t _{LPLH}	Lower Turn-On Propagation Delay (LI Rising to LO Rising)			29	56	ns
t _{HPLH}	Upper Turn-On Propagation Delay (HI Rising to HO Rising)			29	56	ns
t _{MON}	Delay Matching: Lower Turn-On and Upper Turn-Off			2	15	ns
t _{MOFF}	Delay Matching: Lower Turn-Off and Upper Turn-On			2	15	ns
t _{RC} , t _{FC}	Either Output Rise/Fall Time	C _L = 1000 pF		15	-	ns
t _{PW}	Minimum Input Pulse Width that Changes the Output			50		ns
t _{BS}	Bootstrap Diode Turn-Off Time	I _F = 100 mA, I _R = 100 mA		105		ns

(1) Min and Max limits are 100% production tested at 25°C. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods. Limits are used to calculate National's Average Outgoing Quality Level (AOQL).





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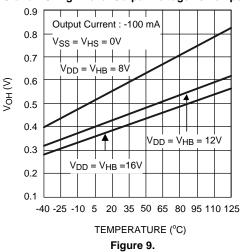
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LO and HO High Level Output Voltage vs Temperature LO and HO Low Level Output Voltage vs Temperature





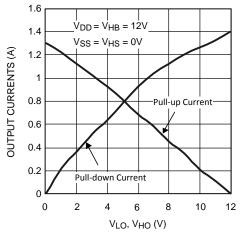
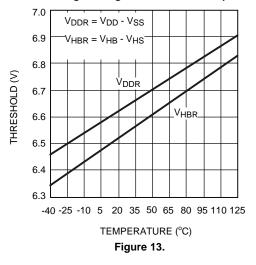
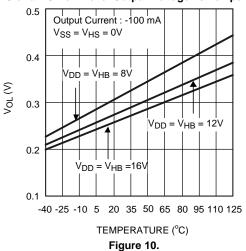


Figure 11.

Undervoltage Rising Thresholds vs Temperature







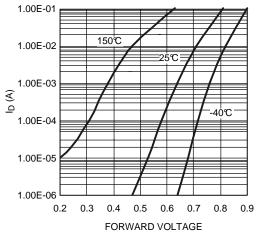
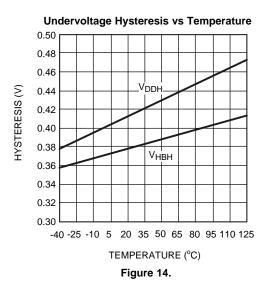


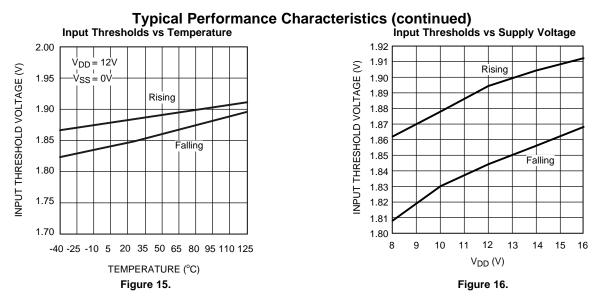
Figure 12.



TEXAS INSTRUMENTS

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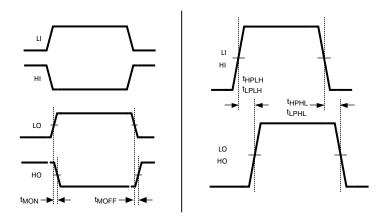
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Timing Diagram



Layout Considerations

The optimum performance of high and low side gate drivers cannot be achieved without taking due considerations during circuit board layout. Following points are emphasized.

- 1. A low ESR / ESL capacitor must be connected close to the IC, and between V_{DD} and V_{SS} pins and between HB and HS pins to support high peak currents being drawn from VDD during turn-on of the external MOSFET.
- 2. To prevent large voltage transients at the drain of the top MOSFET, a low ESR electrolytic capacitor must be connected between MOSFET drain and ground (V_{SS}).
- 3. In order to avoid large negative transients on the switch node (HS) pin, the parasitic inductances in the source of top MOSFET and in the drain of the bottom MOSFET (synchronous rectifier) must be minimized.
- 4. Grounding Considerations:
 - The first priority in designing grounding connections is to confine the high peak currents from charging and discharging the MOSFET gate in a minimal physical area. This will decrease the loop inductance and minimize noise issues on the gate terminal of the MOSFET. The MOSFETs should be placed as close as possible to the gate driver.
 - The second high current path includes the bootstrap capacitor, the bootstrap diode, the local ground referenced bypass capacitor and low side MOSFET body diode. The bootstrap capacitor is recharged on the cycle-by-cycle basis through the bootstrap diode from the ground referenced V_{DD} bypass capacitor. The recharging occurs in a short time interval and involves high peak current. Minimizing this loop length and area on the circuit board is important to ensure reliable operation.

HS Transient Voltages Below Ground

The HS node will always be clamped by the body diode of the lower external FET. In some situations, board resistances and inductances can cause the HS node to transiently swing several volts below ground. The HS node can swing below ground provided:

- 1. HS must always be at a lower potential than HO. Pulling HO more than -0.3V below HS can activate parasitic transistors resulting in excessive current to flow from the HB supply possibly resulting in damage to the IC. The same relationship is true with LO and VSS. If necessary, a Schottky diode can be placed externally between HO and HS or LO and GND to protect the IC from this type of transient. The diode must be placed as close to the IC pins as possible in order to be effective.
- 2. HB to HS operating voltage should be 15V or less . Hence, if the HS pin transient voltage is -5V, VDD should be ideally limited to 10V to keep HB to HS below 15V.
- 3. A low ESR bypass capacitor between HB to HS as well as VDD to VSS is essential for proper operation. The capacitor should be located at the leads of the IC to minimize series inductance. The peak currents from LO and HO can be quite large. Any series inductances with the bypass capacitor will cause voltage ringing at the leads of the IC which must be avoided for reliable operation.



PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
LM5107MA	ACTIVE	SOIC	D	8	95	TBD	Call TI	Call TI		L5107 MA	Samples
LM5107MA/NOPB	ACTIVE	SOIC	D	8	95	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM	-40 to 125	L5107 MA	Samples
LM5107MAX	ACTIVE	SOIC	D	8	2500	TBD	Call TI	Call TI	-40 to 125	L5107 MA	Samples
LM5107MAX/NOPB	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		L5107 MA	Samples
LM5107SD	ACTIVE	WSON	NGT	8	1000	TBD	Call TI	Call TI	-40 to 125	L5107SD	Samples
LM5107SD/NOPB	ACTIVE	WSON	NGT	8	1000	Green (RoHS & no Sb/Br)	SN	Level-1-260C-UNLIM	-40 to 125	L5107SD	Samples
LM5107SDX	ACTIVE	WSON	NGT	8	4500	TBD	Call TI	Call TI	-40 to 125	L5107SD	Samples
LM5107SDX/NOPB	ACTIVE	WSON	NGT	8	4500	Green (RoHS & no Sb/Br)	SN	Level-1-260C-UNLIM	-40 to 125	L5107SD	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ Only one of markings shown within the brackets will appear on the physical device.



9-Mar-2013

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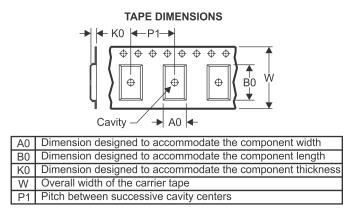
PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM5107MAX	SOIC	D	8	2500	330.0	12.4	6.5	5.4	2.0	8.0	12.0	Q1
LM5107MAX/NOPB	SOIC	D	8	2500	330.0	12.4	6.5	5.4	2.0	8.0	12.0	Q1
LM5107SD	WSON	NGT	8	1000	178.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1
LM5107SD/NOPB	WSON	NGT	8	1000	178.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1
LM5107SDX	WSON	NGT	8	4500	330.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1
LM5107SDX/NOPB	WSON	NGT	8	4500	330.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1

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PACKAGE MATERIALS INFORMATION

17-Nov-2012

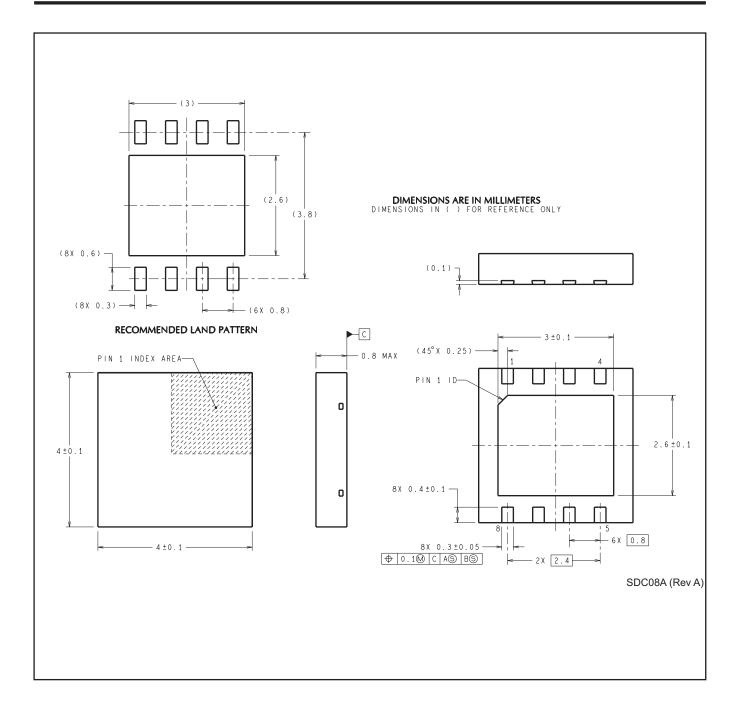


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM5107MAX	SOIC	D	8	2500	349.0	337.0	45.0
LM5107MAX/NOPB	SOIC	D	8	2500	349.0	337.0	45.0
LM5107SD	WSON	NGT	8	1000	203.0	190.0	41.0
LM5107SD/NOPB	WSON	NGT	8	1000	203.0	190.0	41.0
LM5107SDX	WSON	NGT	8	4500	349.0	337.0	45.0
LM5107SDX/NOPB	WSON	NGT	8	4500	349.0	337.0	45.0

MECHANICAL DATA

NGT0008A



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.



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Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
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